Atomistic modeling of the coupling between electric fields and bulk plastic deformation in RF structures



Danny Perez

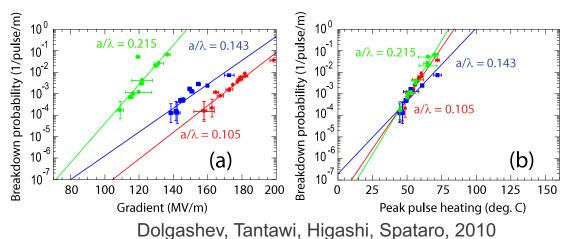


Motivating challenges

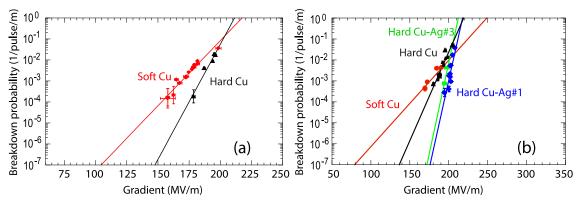
- Compact, low-cost, accelerators require high gradients
- Increase in gradients limited by RF breakdown
- Incidence of breakdown is very well characterized (SLAC, CERN, KEK, INFN-LNF, etc.)
- Microscopic causes are complex:
 - –occurs at fields that are well below what needed of a clean flat Cu surface (~10 GV/m)
 - —implies the formation of surface precursors that locally enhance the field

Motivating questions

- What are these precursors and how they form?
- What controls their formation rate?
 - Gradients
 - Peak pulse heating
 - Chemical composition
 - Bulk microstructure
 - -???



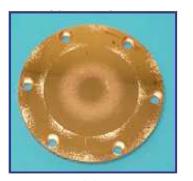




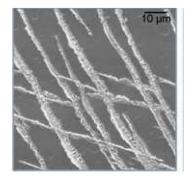
Simakov, Dolgashev, Tantawi, 2018

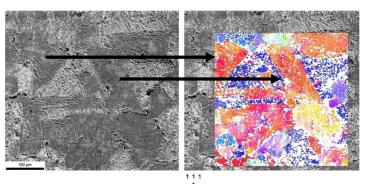
Background

Strong indications that thermal fatigue plays a key role









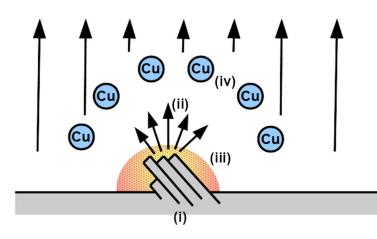
Laurent, Tantawi, Dolgashev, Nantista, 2011



This mechanism couples to composition/microstructure

Background

In fatigue, surface deformation is mediated by dislocations incoming from the bulk



Engelberg et al, 2019

- Plastic deformation in real materials is extremely complex
- Heroic efforts to model evolution of dislocation distribution under field [e.g., MDDF by Ashkenazy et al.]
- Important takeaway: key parameter is β, which relates applied E to resolved shear stress

Our approach

- Goal: begin to understand the coupling between the surface tractions induced by E and plastic deformation
- Idealized setting
- Main tool: Atomistic level modeling using Molecular Dynamics

Summary of today's talk:

- Atomistic charge equilibration model
- Plastic deformation under E field

Levels of theory

Quantum description:

- Density functional theory (DFT)
- Strengths:
 - Very accurate
 - Natural description of E
- Weakness:
 - Very expensive (scales as N_{electrons}³)
 - Small systems (~few 100 atoms):
 - Static or short dynamic simulations (~ps)

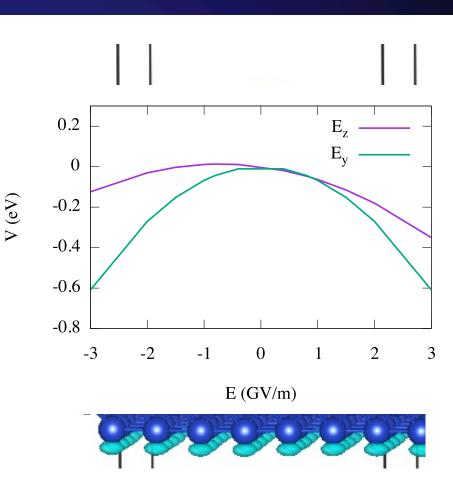
Classical description:

- Molecular dynamics
- Strengths:
 - Relatively fast
 - "Large" systems (>10⁶ atoms)
 - "Long" simulations (10⁻⁶-10⁻³ s):
- Weakness:
 - E has to be included "by hand"
 - still << engineering scales</p>

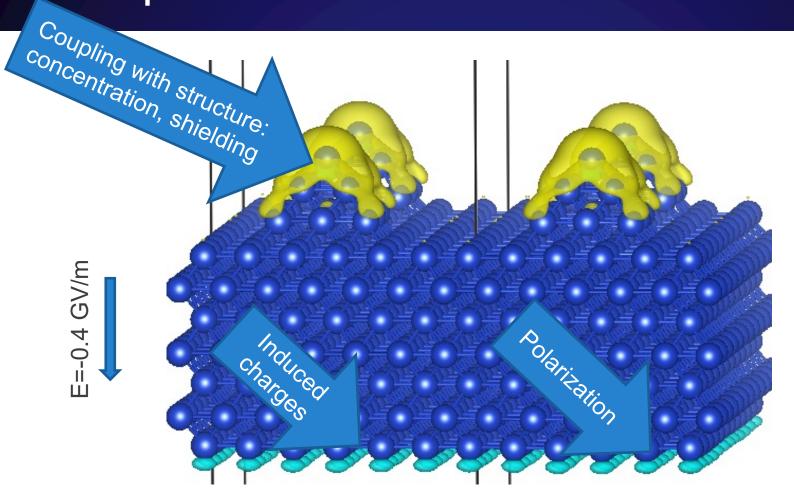
Classical MD

In conventional MD, charges are typically implicit or fixed. In order to capture field effects, we need a **charge equilibration model.**

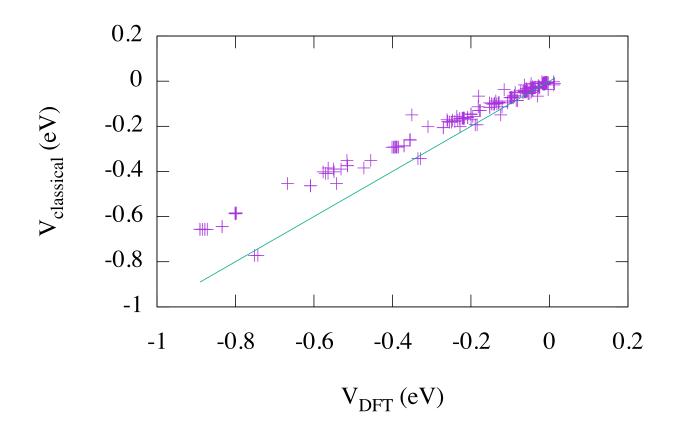
- Parameterize the empirical electronic Hamiltonian by fitting to quantum data
- During MD: dynamically assign charges to minimize electronic energy



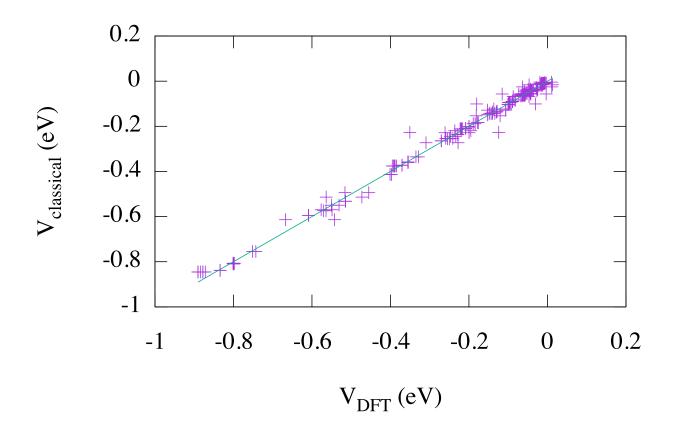
Example of DFT results



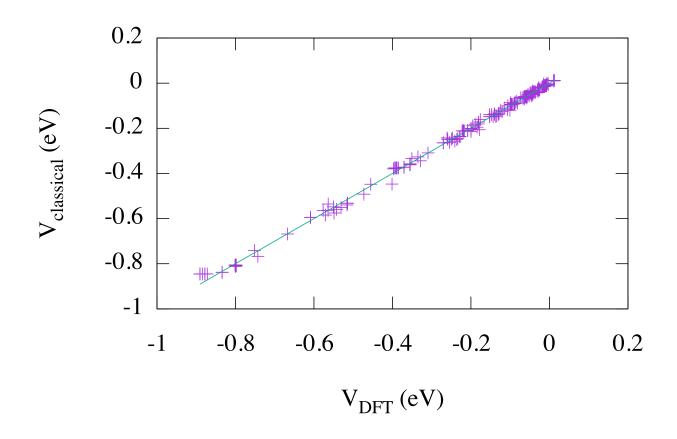
Validation: no polarizability, no intrinsic dipole



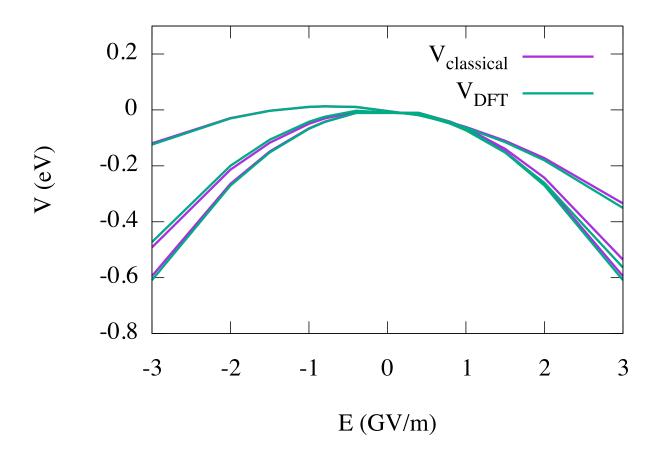
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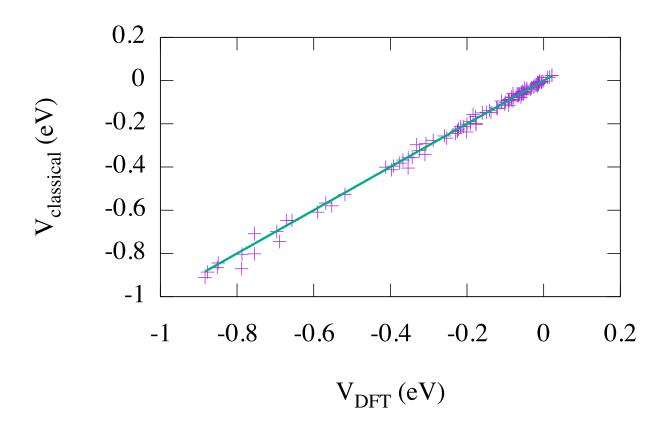
Validation: polarizability, intrinsic dipole



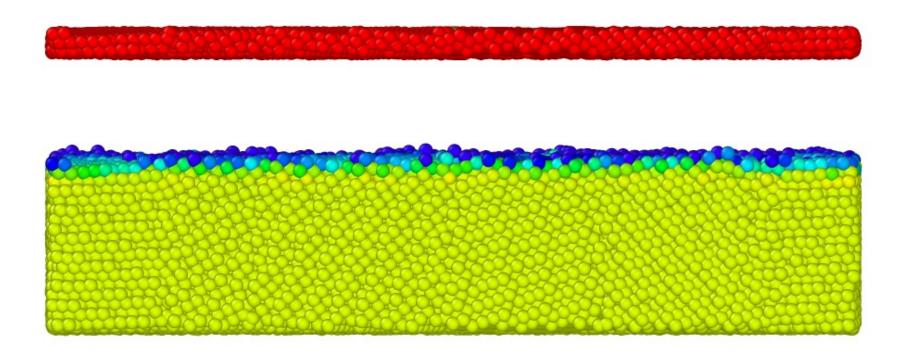
Intrinsic dipole



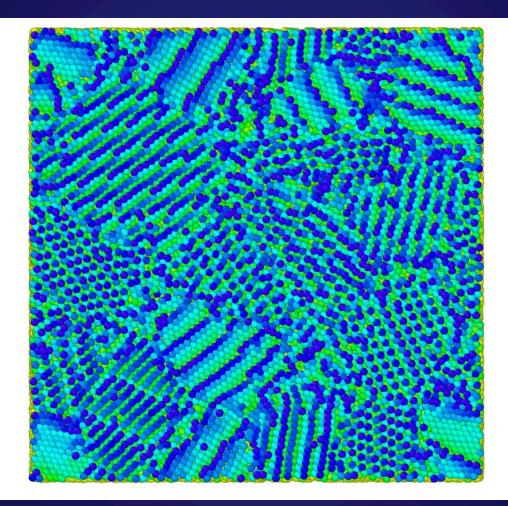
Validation Cu/Ag: polarizability, intrinsic dipole



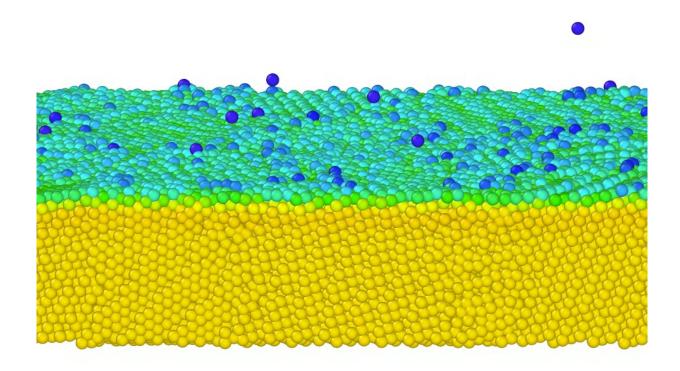
Model #1: Large-scale MD



Large-scale MD

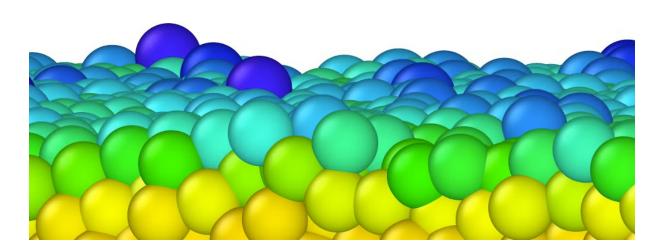


Large-scale MD



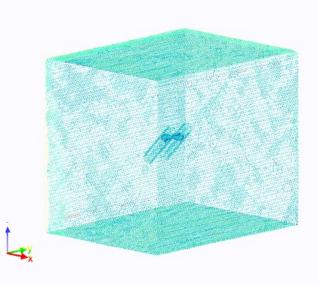
Large-scale MD

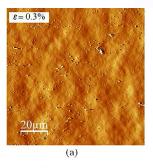


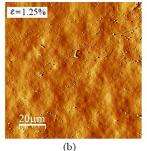


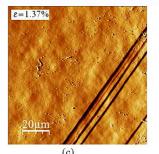
Plastic deformation under E

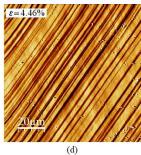
- Fully-developed dislocation microstructure is incredibly complex
- Considering unit steps in isolation
- First target: 1D periodic array of Frank Read sources







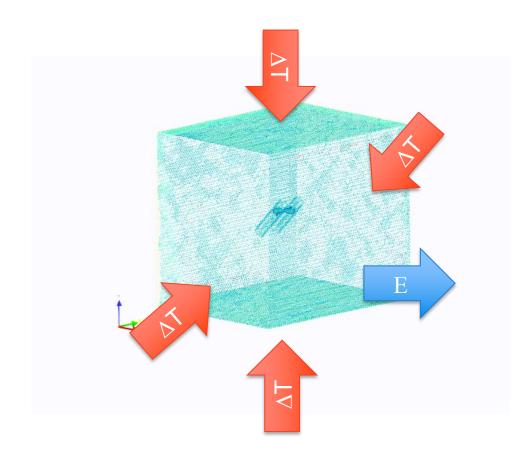




Setup

Driving forces:

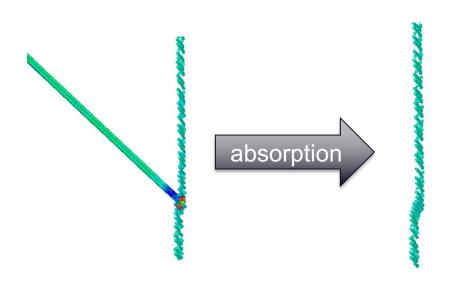
- Lateral thermal stress due to RF heating
- Surface traction due to fieldinduced surface charges



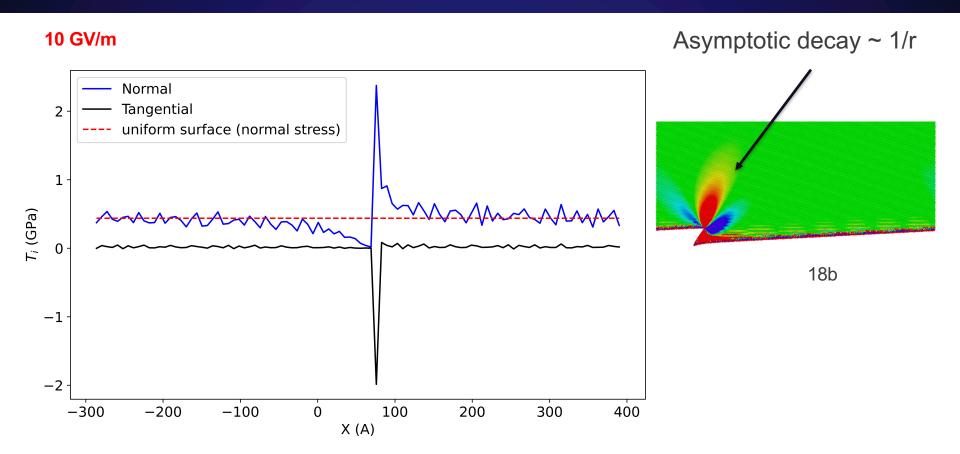
Setup

Driving forces:

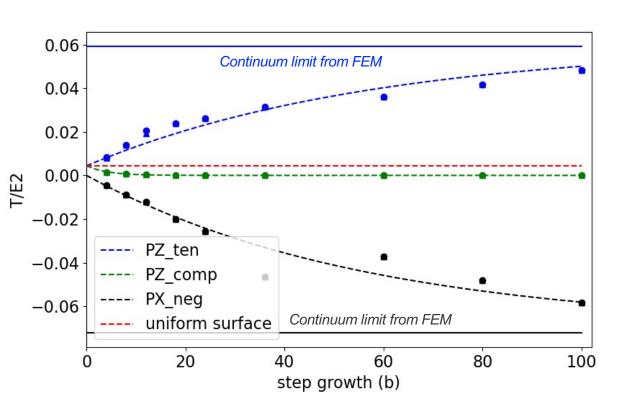
- Lateral thermal stress due to RF heating
- Surface traction due to induced surface charges
- Field enhancement due surface steps (MD-QEq)

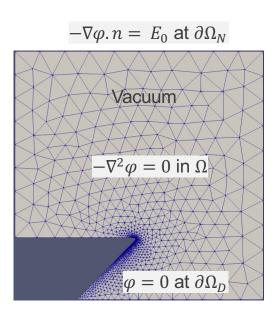


RSS enhancement due to surface steps



RSS enhancement due to surface steps



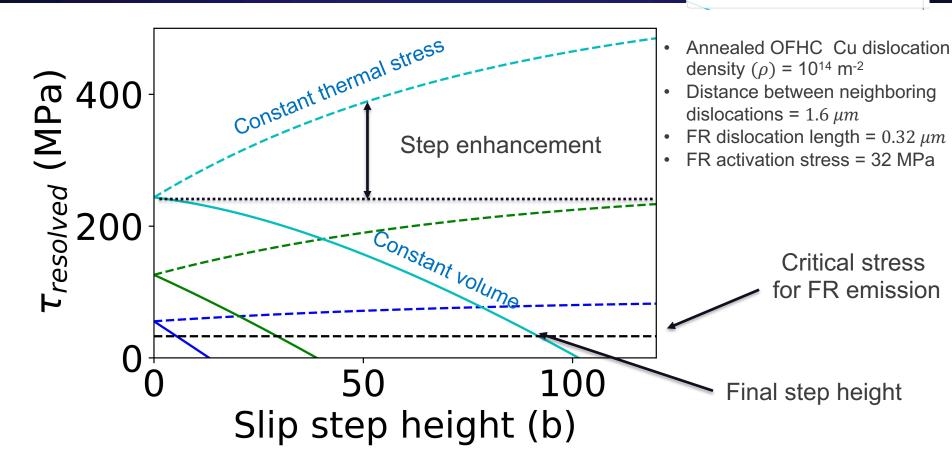


Repeated emission

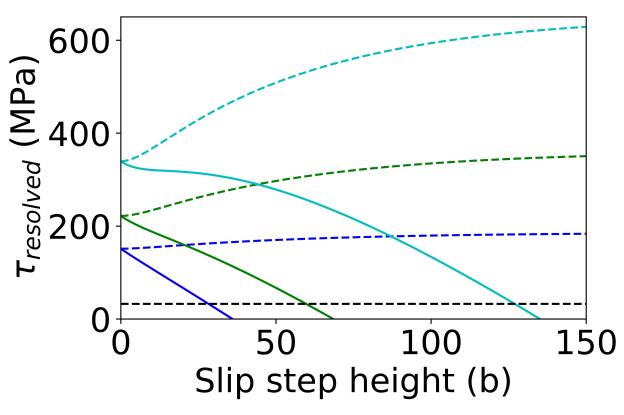
- At fixed thermal stress, the FR source could emit indefinitely
- At fixed volume, the source gradually exhausts itself, as the plastic strain relaxes the driving force from the thermal stress
- What is the impact of E on the final step height?

Repeated emission: $\Delta T = 20^{\circ}\text{C}$

5.0GV/m Net stress10.0GV/m Net stress15.0GV/m Net stress



Repeated emission: $\Delta T = 80^{\circ}\text{C}$

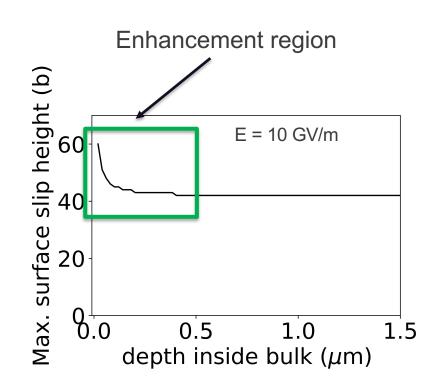


5.0GV/m Net stress10.0GV/m Net stress15.0GV/m Net stress

- Annealed OFHC Cu dislocation density $(\rho) = 10^{14} \text{ m}^{-2}$
- Distance between neighboring dislocations = 1.6 μm
- FR dislocation length = $0.32 \mu m$
- FR activation stress = 32 MPa

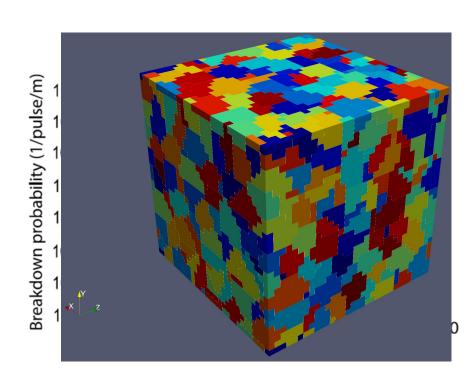
Repeated emission: step enhancement

- Electric fields can assist in dislocation emission, at very high fields. Small effect at typical gradients.
- Thermal stresses from RF losses main driving force
- Field coupling with surface steps can enhance dislocation emission at short range (~1 μm, comparable to RF heating range) and high field
- Could play a role in nearbreakdown conditions

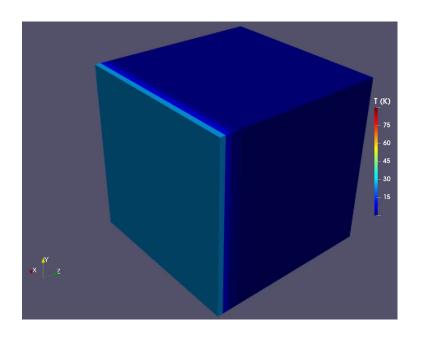


In progress: Crystal Plasticity

- Microstructure plays a role in breakdown
- Very difficult to capture such effects with MD, analytic models require lots of assumptions
- Currently implementing coupled thermo-plastic solver to better understand surface deformation
- Future task: include E coupling



In progress: Crystal Plasticity



e33 3.0e-03 0.0025 0.002 0.0015 0.0005 0 -0.0005 -1.0e-03

Temperature distribution

Plastic strain distribution

Conclusion

- We have developed an accurate, allatomistic, method to include E in classical MD simulations
- We have applied this technique to the coupling of E with FR plasticity through surface features.
- High local fields are required for significant enhancement. Could play a role near breakdown.



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